

ABSTRACT OF THE DISCLOSURE

An LSI which makes scan testing possible without compromising security is provided. Flip-flops that constitute a scan chain are reset
5 when scan testing is initiated or terminated by the edges of a mode signal for switching between normal operations and scan testing. In addition, during scan testing, internal memory means is made inaccessible. Further, a dummy flip-flop that operates only during scan testing is connected to the scan chain, and shifting out by the scan chain during
10 normal operations is made impossible.